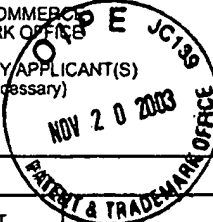




FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 00862.022497.1		APPLICATION NO. 10/687,743	
				APPLICANT KIYOFUMI SAKAGUCHI, et al.			
				FILING DATE October 20, 2003		GROUP NYA	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	5,206,749	04/27/93	Zavracky et al.	359	59		
	5,256,562	10/26/93	Vu et al.	437	86		
	5,811,348	09/22/98	Matsushita et al.	438	455		
	6,107,213	08/22/00	Tayanaka et al.	438	762		
	5,856,229	01/05/99	Sakaguchi et al.	438	406		
	5,985,742	11/16/99	Henley et al.	438	515		
	6,075,280	06/13/20	Yung et al.	257	620		
	6,136,668	10/24/00	Tamaki et al.	438	462		
	6,186,384	02/13/01	Sawada	225	2		
	6,190,937	02/20/01	Nauagawa, et al.	438	67		
	6,222,513	03/10/98	Howard, et al.	345	84		
	6,258,698	07/10/01	Iwasaki, et al.	438	455		
	6,306,729	10/23/01	Sauaguchi, et al.	438	458		
	6,331,208	12/18/01	Nishida, et al.	117	89		
	6,342,433	01/29/02	Ohmi, et al.	438	455		
	6,382,292	05/07/02	Ohmi, et al.	156	584		
	6,465,329	10/15/02	Glenn	438	642		
		2002/0076904	06/20/02	Imler	438	642	
TL	2002/0100941	08/01/02	Yonehara et al.	257	359		
EXAMINER 				DATE CONSIDERED 02/15/05			

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		APPLICANT KIYOFUMI SAKAGUCHI, et al.	
		FILING DATE October 20, 2003	GROUP NYA

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
TL	2002/0102758	08/01/02	Yonehara et al.	438	30		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
TL 1 122 794	08/08/01	Europe					
858 110	08/12/98	Europe					
849 788	06/24/98	Europe					
886 300	12/23/98	Europe					
9-312349	12/02/97	Japan					
TL 11-316397	11/16/99	Japan					

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		
TL		Shimoda, T., et al: "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5-8, 1999, New York, NY: IEEE, US, Aug. 1, 1999 (1999-08-01), pages 289-292, XP000933199 ISBN: 0-7803-5411-7.

EXAMINER 	DATE CONSIDERED 02/15/05
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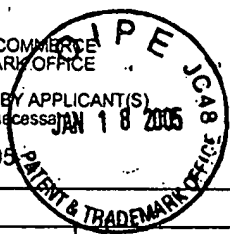
FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. <b>00862.022497.1</b>		APPLICATION NO. <b>10/687,743</b>	
<div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block;">             MAY 25 2004              PATENT &amp; TRADEMARK OFFICE           </div>				APPLICANT <b>KIYOFUMI SAKAGUCHI, ET AL.</b>			
				FILING DATE <b>October 20, 2003</b>			GROUP <b>N.Y.A.</b>
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TL		6,682,963	01/27/04	Ishikawa	438	149	
		5,757,456	05/26/98	Yamazaki, et al.	349	151	
		6,627,487	09/30/03	Zhang	438	166	
		6,455,398	09/24/02	Fonstad, Jr. et al.	438	459	
		6,500,731	12/31/02	Nakagawa, et al.	438	455	
		6,602,761	08/05/03	Fukunaga	438	459	
		6,677,183	01/13/04	Sakaguchi, et al.	438	113	
TL		6,682,990	01/27/04	Iwane, et al.	438	458	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
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Date Submitted: January 13, 2005			APPLICANT <b>KIYOFUMI SAKAGUCHI, ET AL.</b>			
FILING DATE <b>October 20, 2003</b>			GROUP <b>2814</b>			



U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
TL	5,597,766	01/28/1997	Neppi	437	226		
TL	5,888,882	03/30/1999	Igel, et al.	438	460		
TL	6,017,804	01/25/2000	Freund, et al.	438	460		

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
TL	0 603 973 A2	06/29/1994	Europe				
TL	WO 93/21663	10/28/1993	PCT				
TL	55-145354	11/12/1980	Japan			Abstract	

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							

EXAMINER		DATE CONSIDERED	<b>02/08/05</b>
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